

# CRYOEM 001 : TOOLS OF THE TRADE - MICROSCOPES AND DETECTORS

NCCAT Embedded Training — Master Class series

September 2020

NATIONAL CENTER FOR  
CRYOEM ACCESS & TRAINING



New York Structural  
Biology Center

SIMONS ELECTRON  
MICROSCOPY CENTER



# CRYOEM 001 : SINGLE PARTICLE MASTERCLASS

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Introduction to cryoEM: SPA

Building a cryoEM toolkit

EM compatible samples

EM support films and grids

Sample preparation

Tools of the trade:

microscopes and detectors

Microscope operations

Data collection strategies

Data assessment & QC

Data processing:

cryoEM IT infrastructure

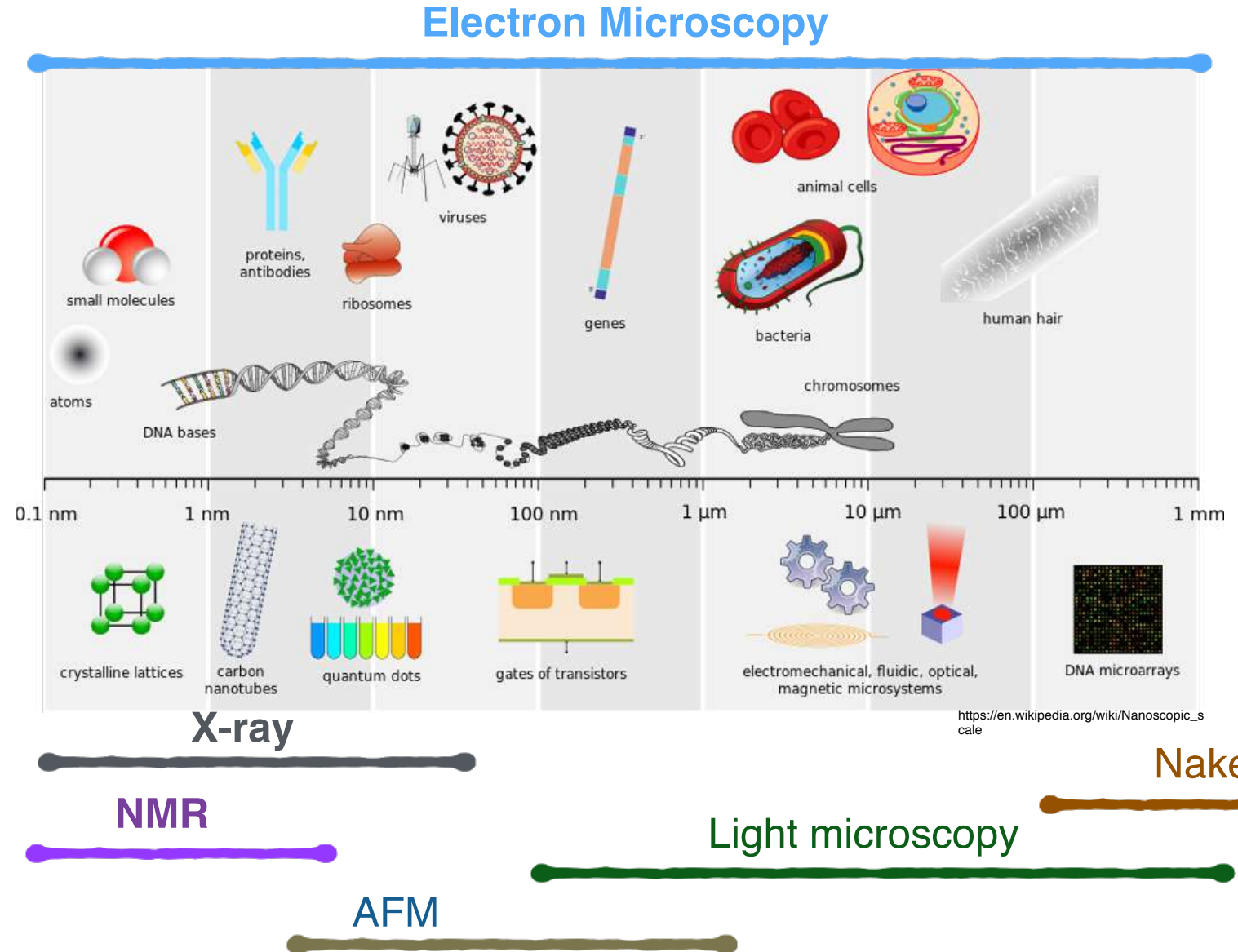
On-the-fly feedback

3D Reconstruction

Visualization and validation



# CRYOEM: SCALE WITHIN BIOLOGY



# WHAT BROUGHT ABOUT THE RESOLUTION REVOLUTION

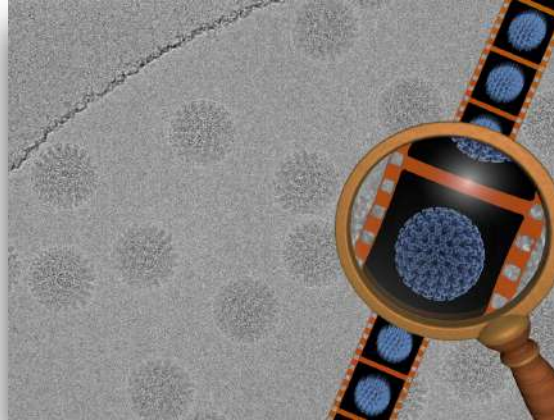
(~2012-2014)

## Hardware

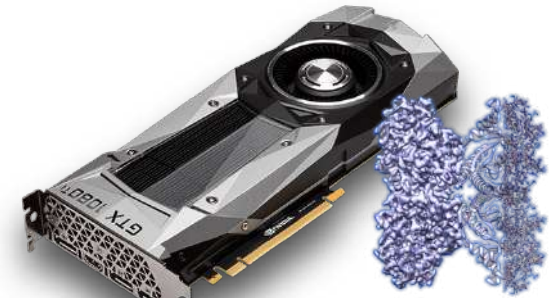
Microscopes



Direct Detectors



Computers

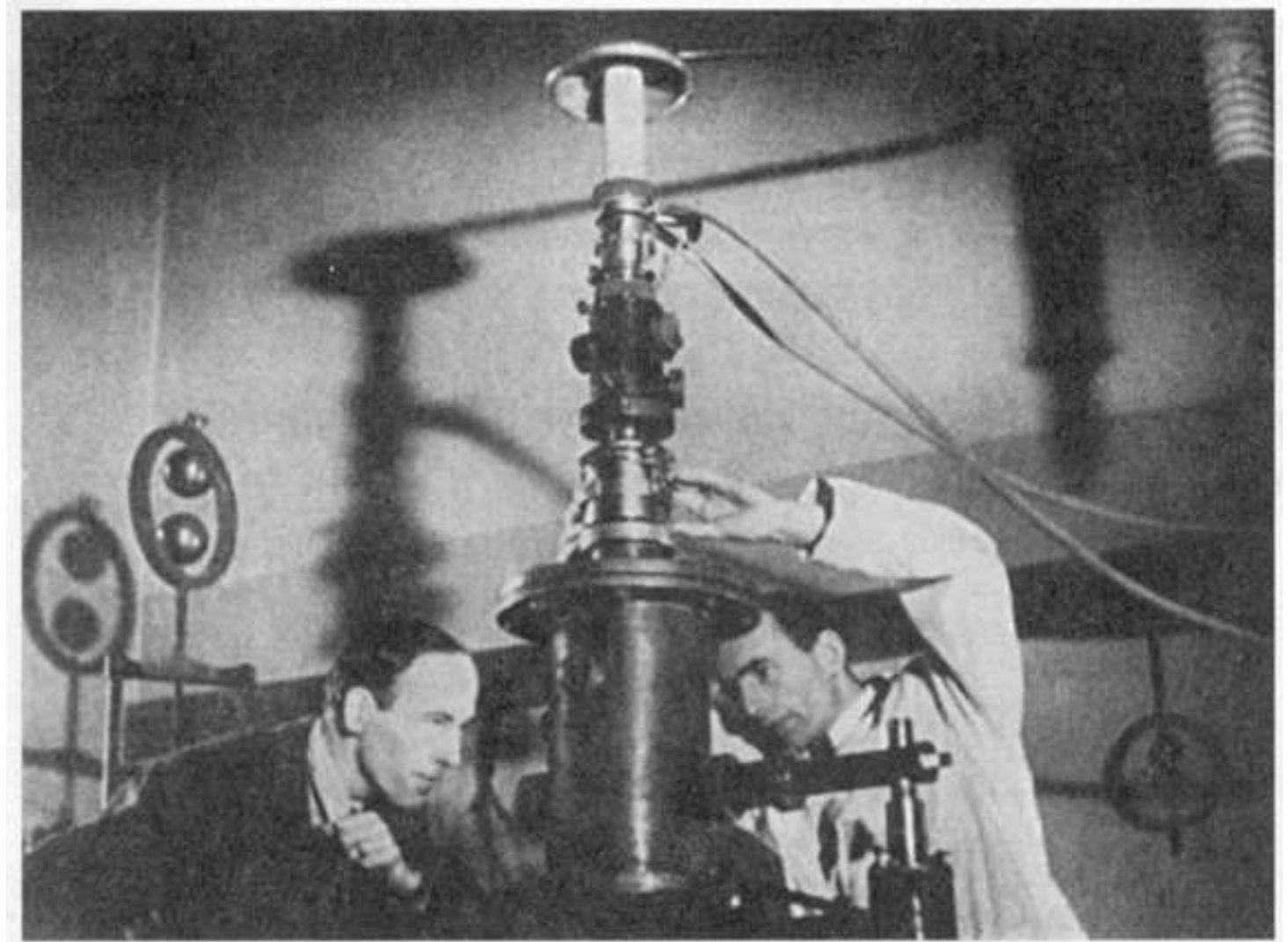


2012->2017  
Cost reduced by 100x

# THE ELECTRON MICROSCOPE

Ruska and Knoll in Berlin in the  
early 1930s

-Wikipedia



**WHY ELECTRONS**

Transmitted electrons

Characteristic X-rays

SE

N

K

L

M

$e^-$

$e^-$

$e^-$

Elastic scattering

Inelastic scattering

Main beam electrons

Transmitted electrons

Characteristic X-rays

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The diagram illustrates the interaction of a beam of electrons with an atom. The atom is represented by a central nucleus (N) and three concentric electron shells labeled K, L, and M. A vertical dashed line represents the incident electron beam. Three types of interactions are shown:
 

- Elastic scattering:** An electron from the beam hits an outer shell electron, and both are deflected without energy loss.
- Inelastic scattering:** An electron from the beam hits an inner shell electron, causing it to jump to a higher shell and emit a characteristic X-ray.
- Transmitted electrons:** Electrons that pass through the atom without interacting.

 A legend at the bottom right indicates that blue dots represent 'Main beam electrons'.

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# WHY ELECTRONS

## Pros

Small wavelength

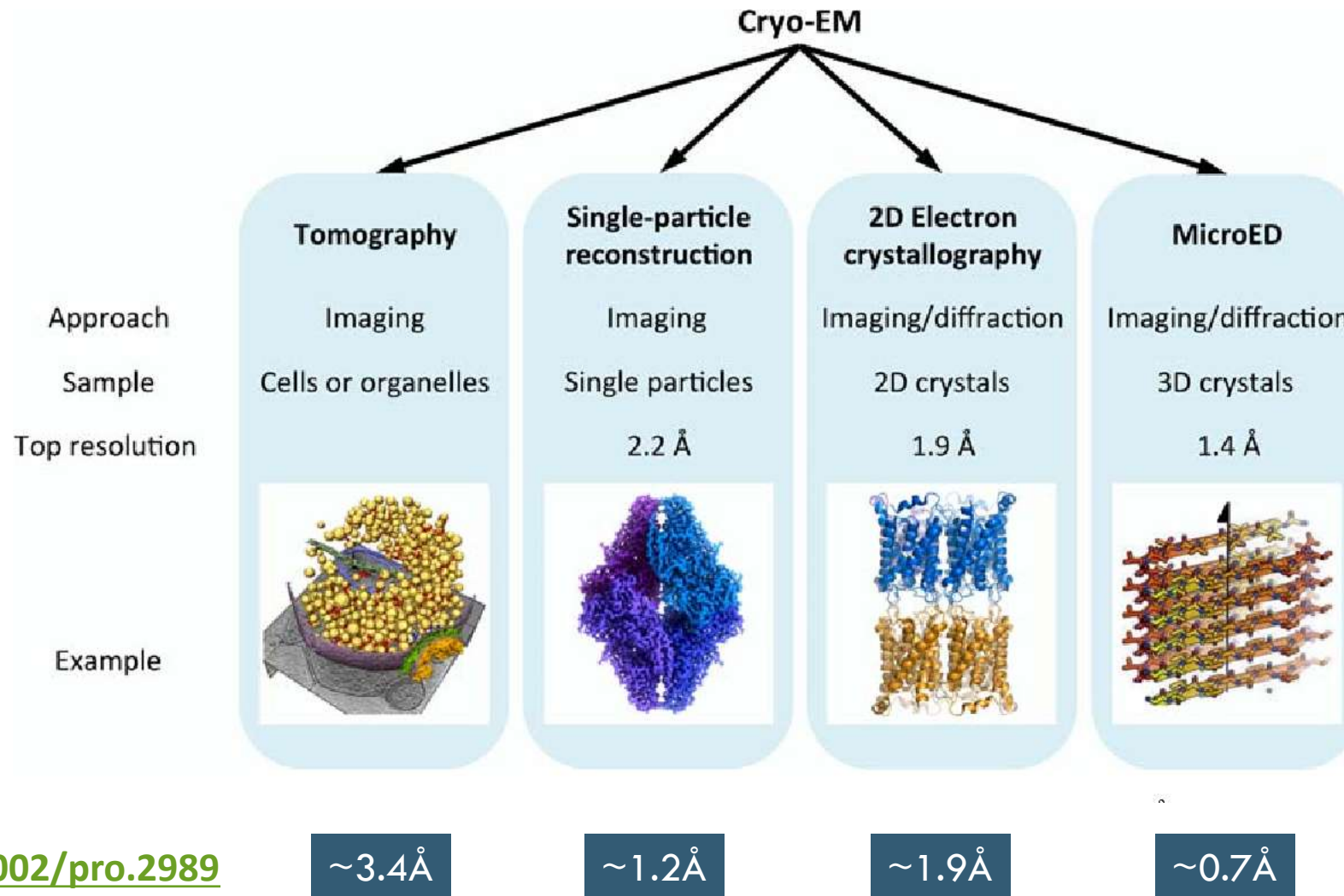
Can be focused

## Cons

Damages sample  
worse with faster electrons

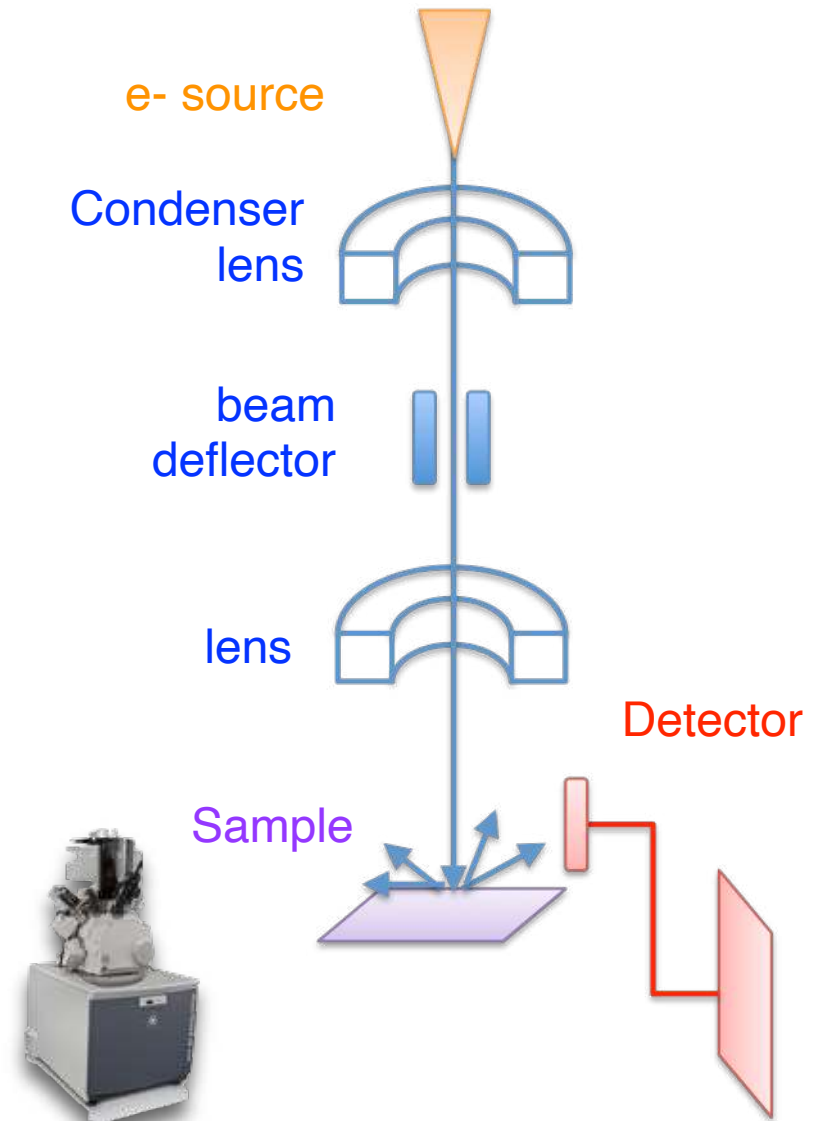
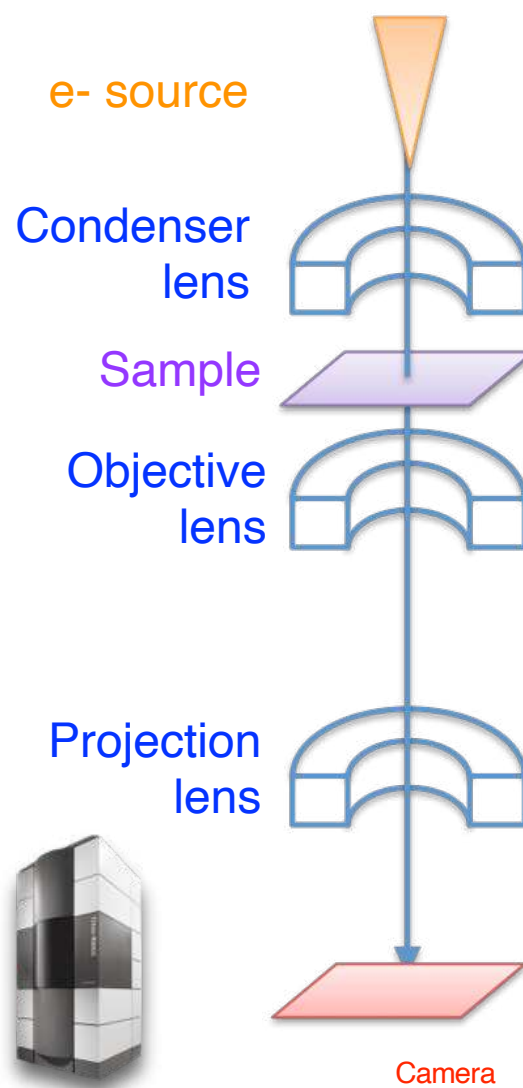
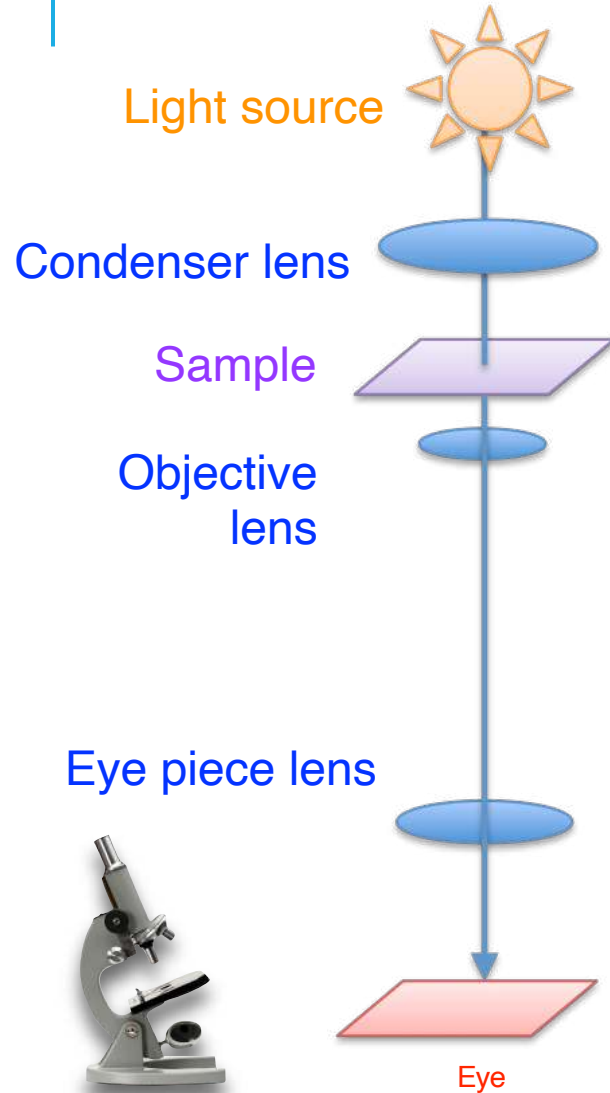
Poor penetration  
better with faster electrons

# CRYOEM MODALITIES AND TOOLS

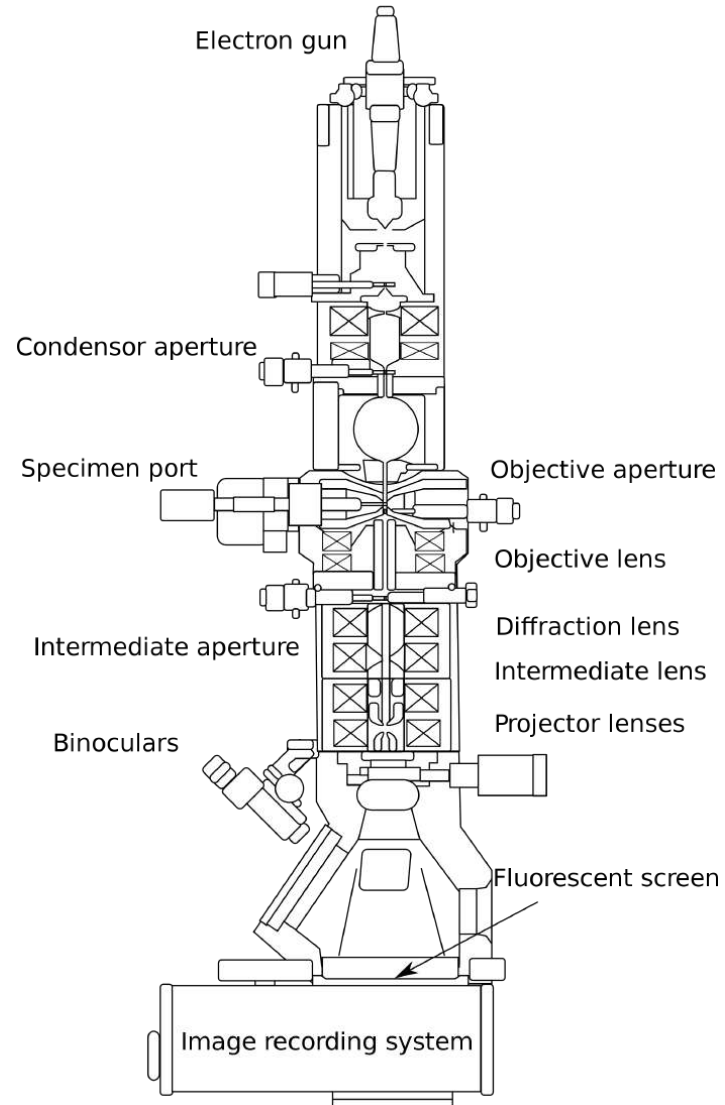




# CRYOEM TOOLS



# MAIN PARTS OF AN EM



**Electron sources**



**Vacuum systems**



**Lenses**

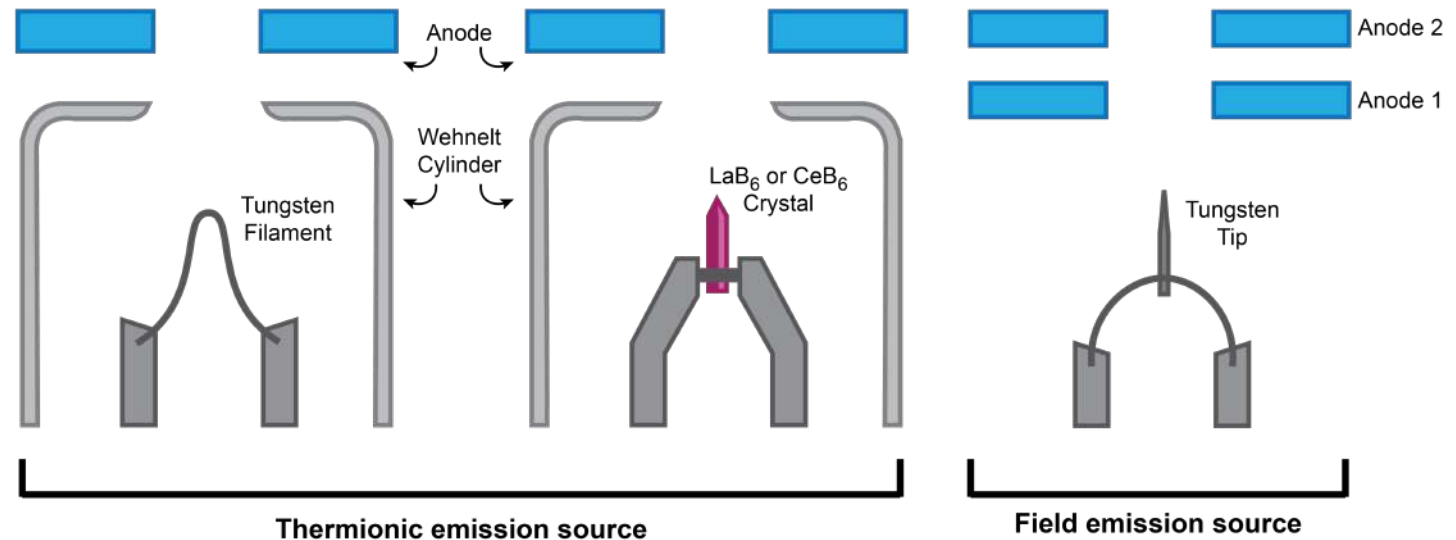


**Detectors**



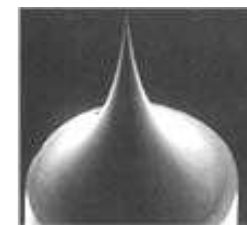
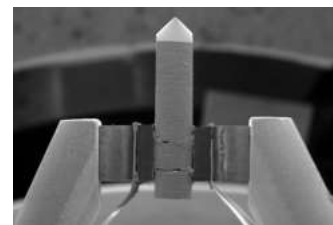
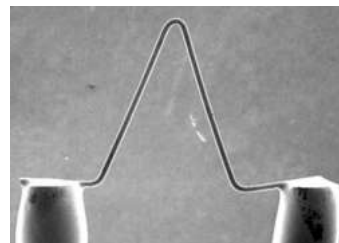
# ELECTRON SOURCES

What are the 3 main kinds of electron sources?



[www.thermofisher.com](http://www.thermofisher.com)

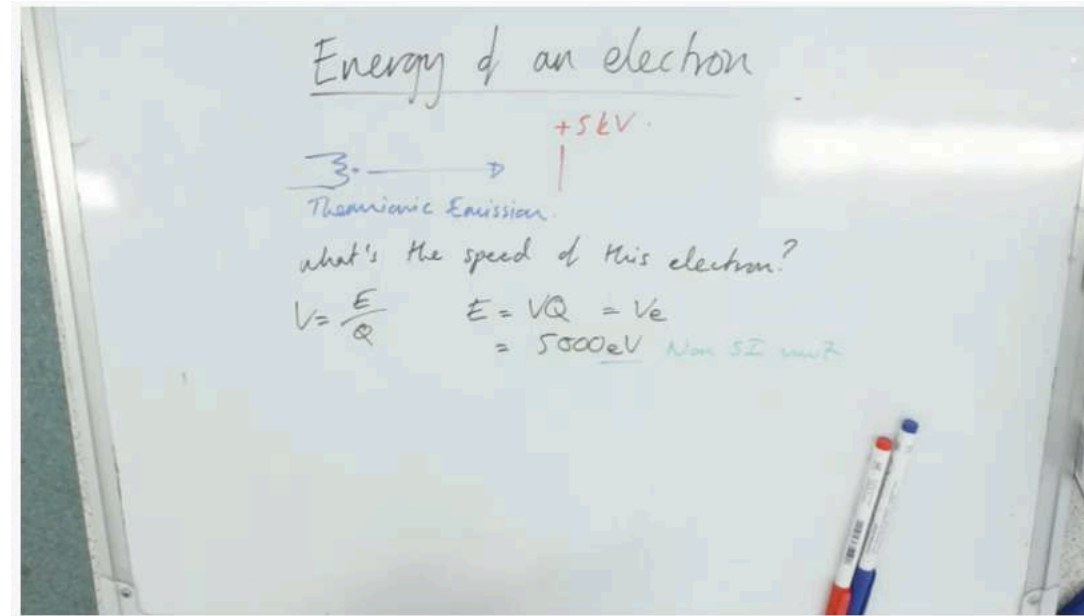
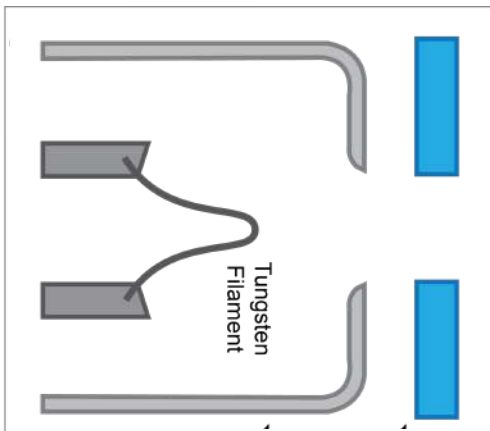
[nanoscience.com](http://nanoscience.com)





# ELECTRON SOURCES

How fast are the electrons moving?



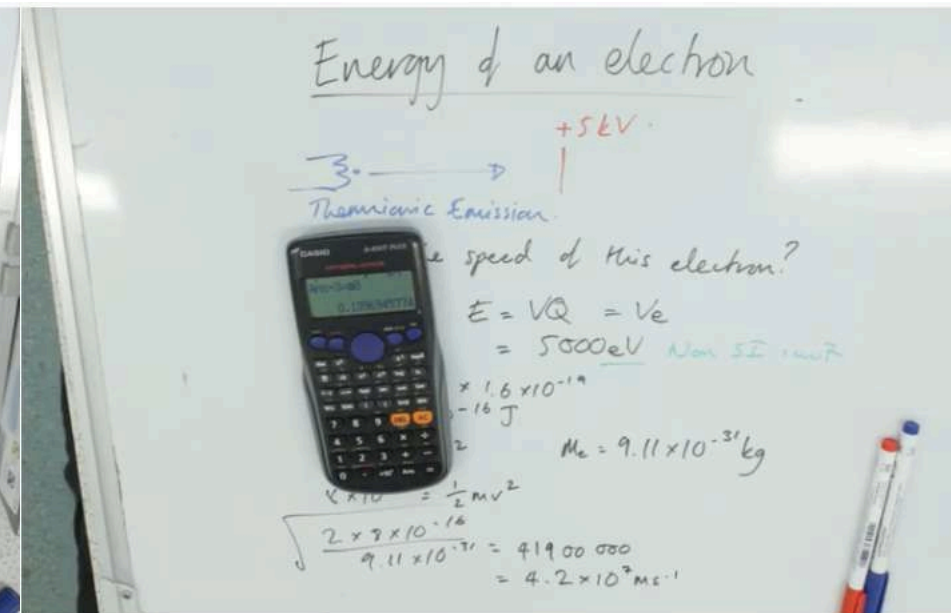
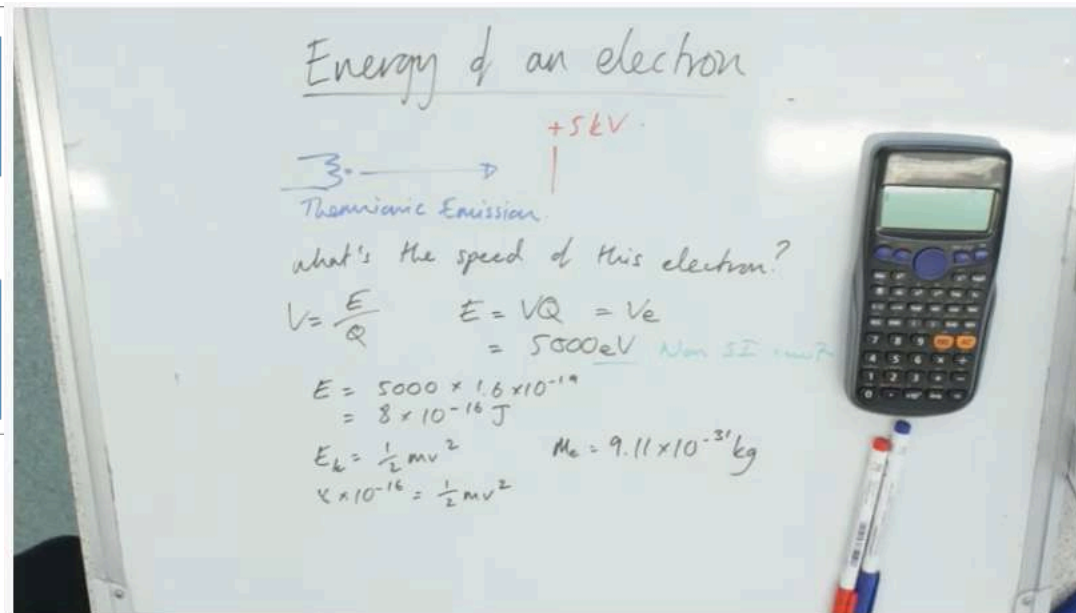
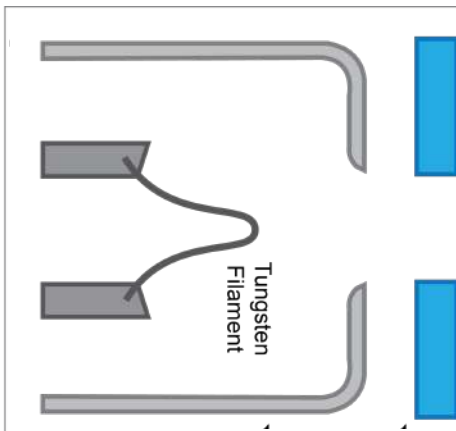
<https://www.youtube.com/watch?v=tYCET6vYdYk>





# ELECTRON SOURCES

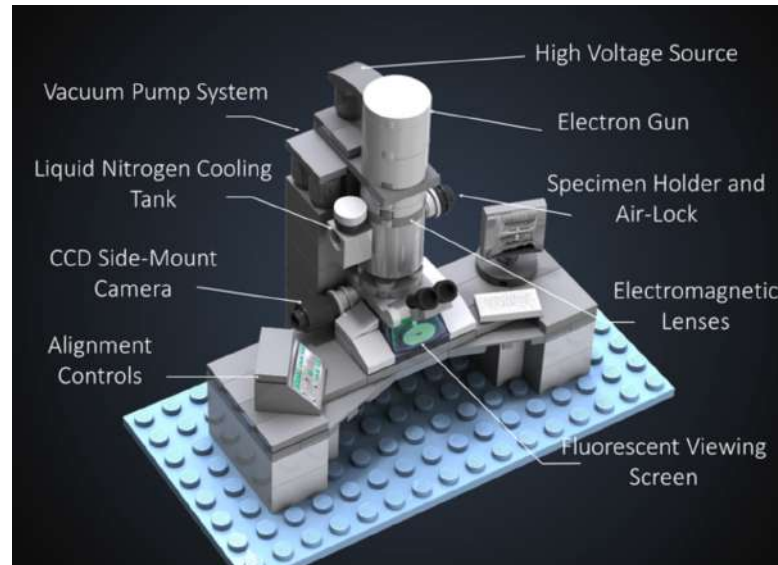
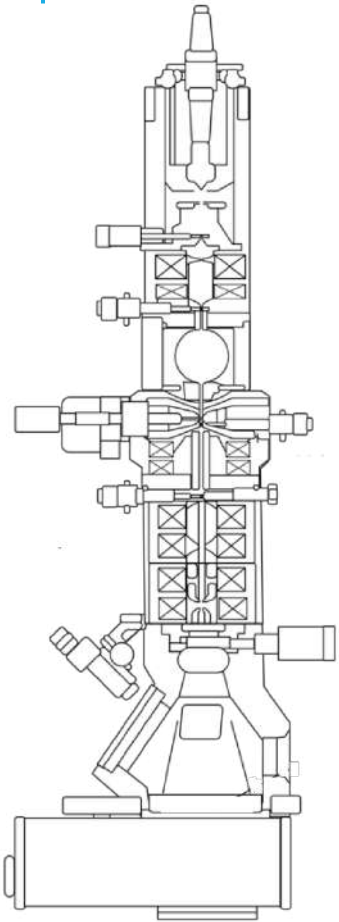
How fast are the electrons moving?



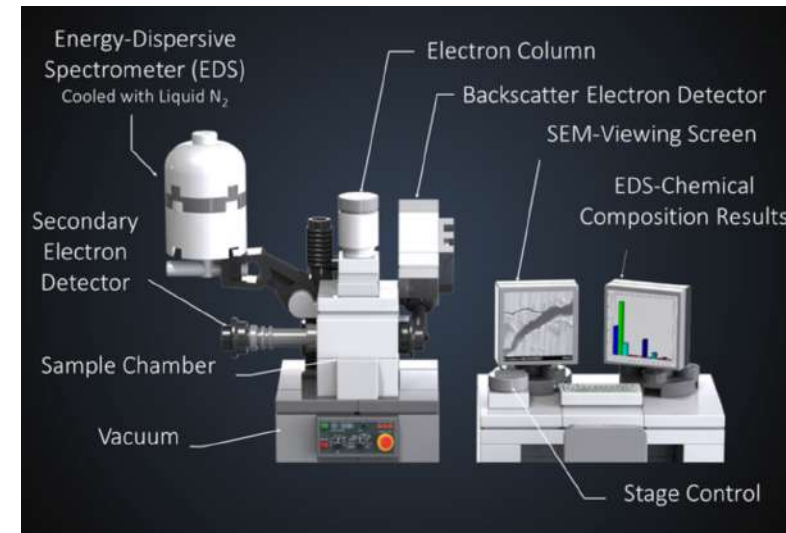
<https://www.youtube.com/watch?v=tYCET6vYdYk>



# ELECTRON SOURCES & TYPES OF EMS

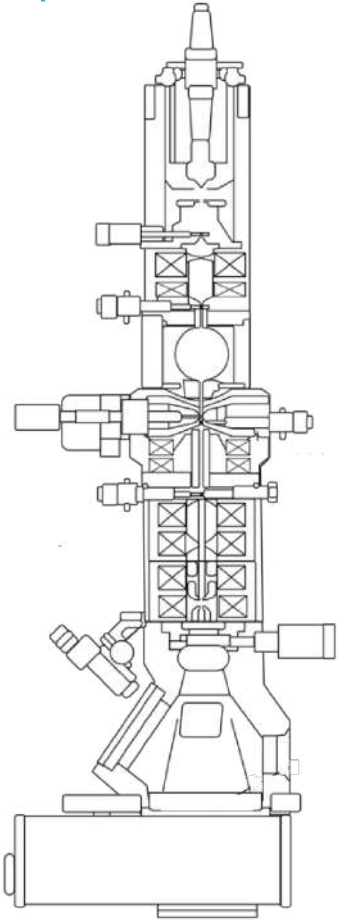


<https://ideas.lego.com/projects/102281>





# ELECTRON SOURCES & TYPES OF EMS



**80-120 kV:** JEM 1230; Tecnai T12

W or LaB<sub>6</sub>

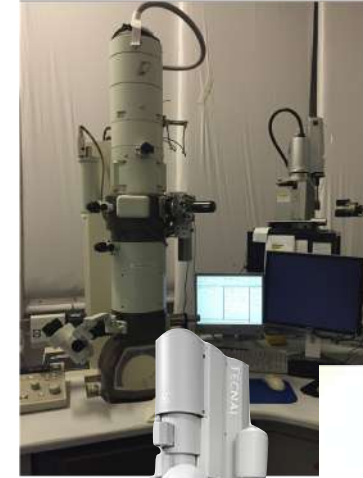
High contrast & robust  
sub-nm resolution

**200 kV:** JEM 2100F, Tecnai F20, Talos, Artica  
FEG

2+ Å resolution (3.5-4 Å)

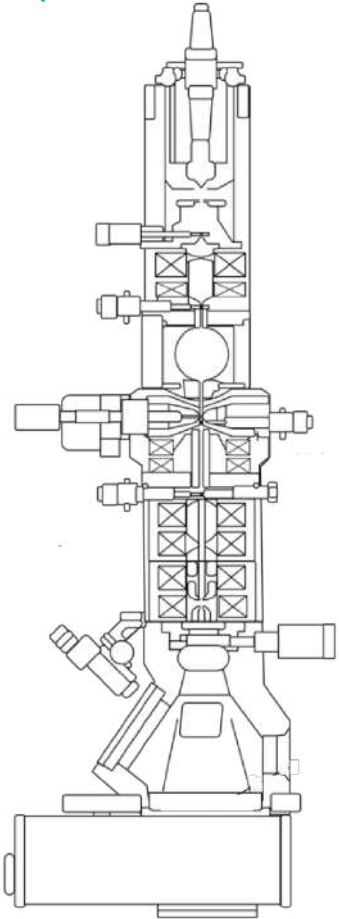
**300 kV:** JEM 3200FSC, cryo-ARM, Krios, Polara  
FEG

Smaller effect on unwanted lens aberration  
1.5-3 Å resolution





# ELECTRON SOURCES & TYPES OF EMS

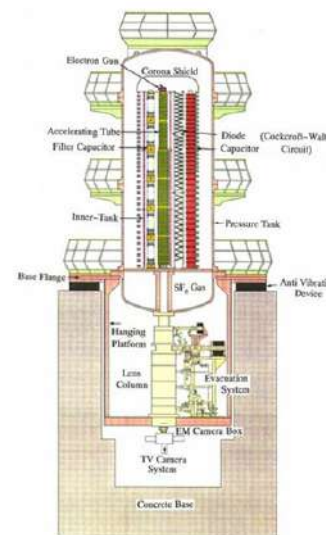


**1-1.2 MV:** Hitachi, JEOL  
LaB<sub>6</sub>



[uhvem.osaka-u.ac.jp](http://uhvem.osaka-u.ac.jp)

**3 MV:** Hitachi H3000  
LaB<sub>6</sub>

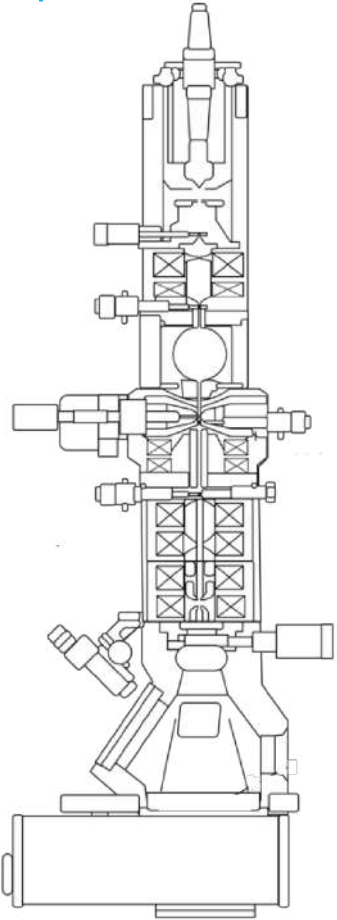






# VACUUM SYSTEMS

Why do we need a vacuum?



**Beam coherence** - at STP mean free path  $\sim 1$  cm

**Insulation** - interaction between e- and air

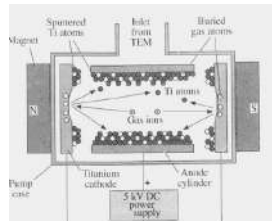
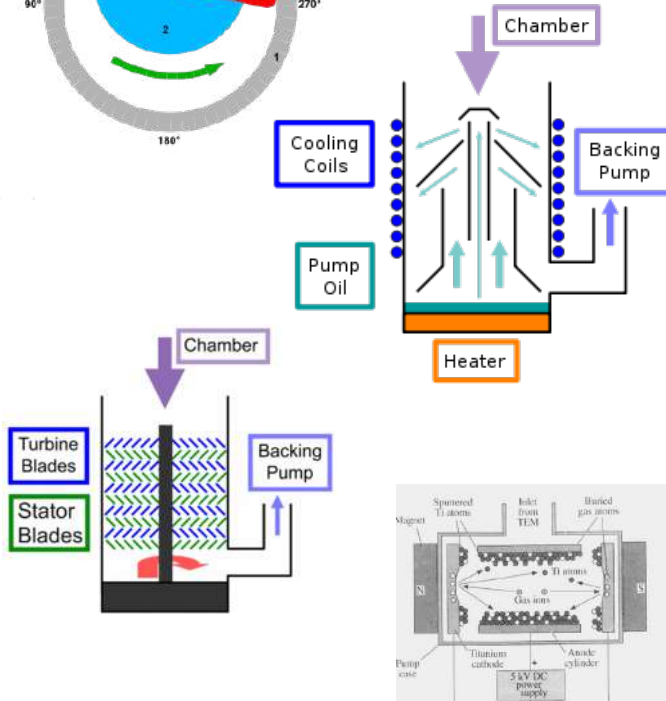
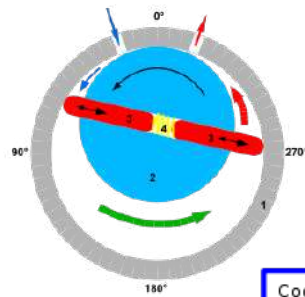
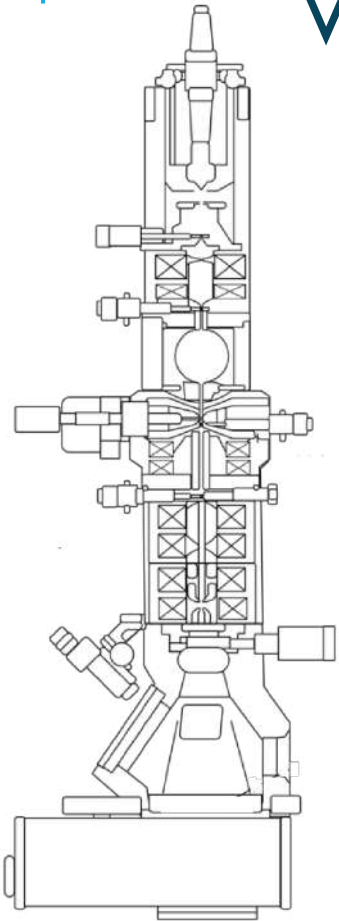
**Filament** - O<sub>2</sub> will burn out source

**Contamination** - reduce interaction gas, e-beam and sample



# VACUUM SYSTEMS

What types of pumps do we have?



wikipedia.com

$1 \text{ mm Hg} = 1 \text{ Torr} = 10^2 \text{ Pa}$   
 $1 \text{ atm} = 760 \text{ Torr} = 7.5 \times 10^4 \text{ Pa}$

**PVP / Rotary**  $1\text{-}10^{-3} \text{ Torr}$  |  $>0.1 \text{ Pa}$

**Diffusion**  $10^{-3}\text{-}10^{-6} \text{ Torr}$  |  $0.1\text{-}10^{-4} \text{ Pa}$

**Turbo**  $10^{-6}\text{-}10^{-9} \text{ Torr}$  |  $10^{-4}\text{-}10^{-7} \text{ Pa}$

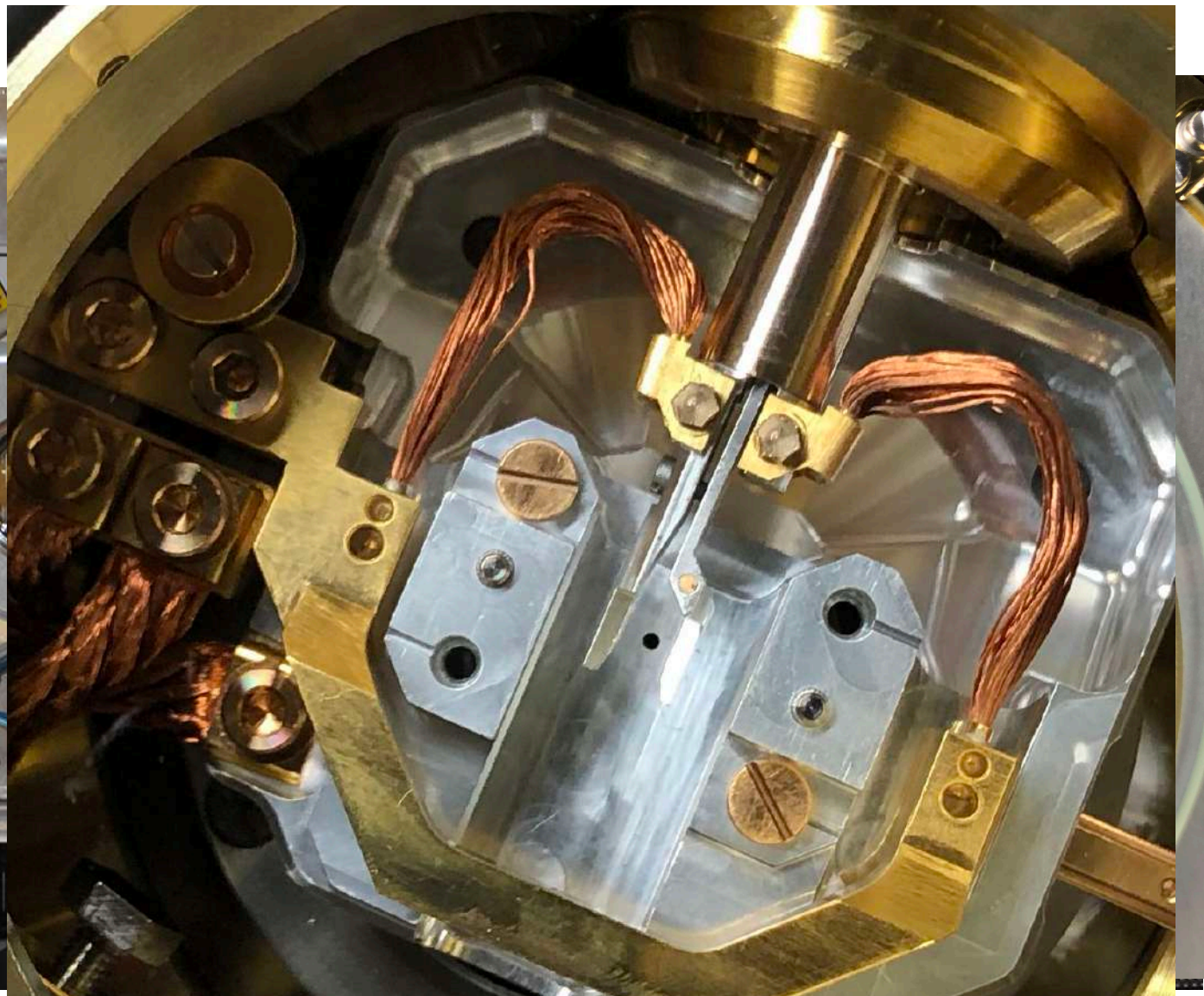
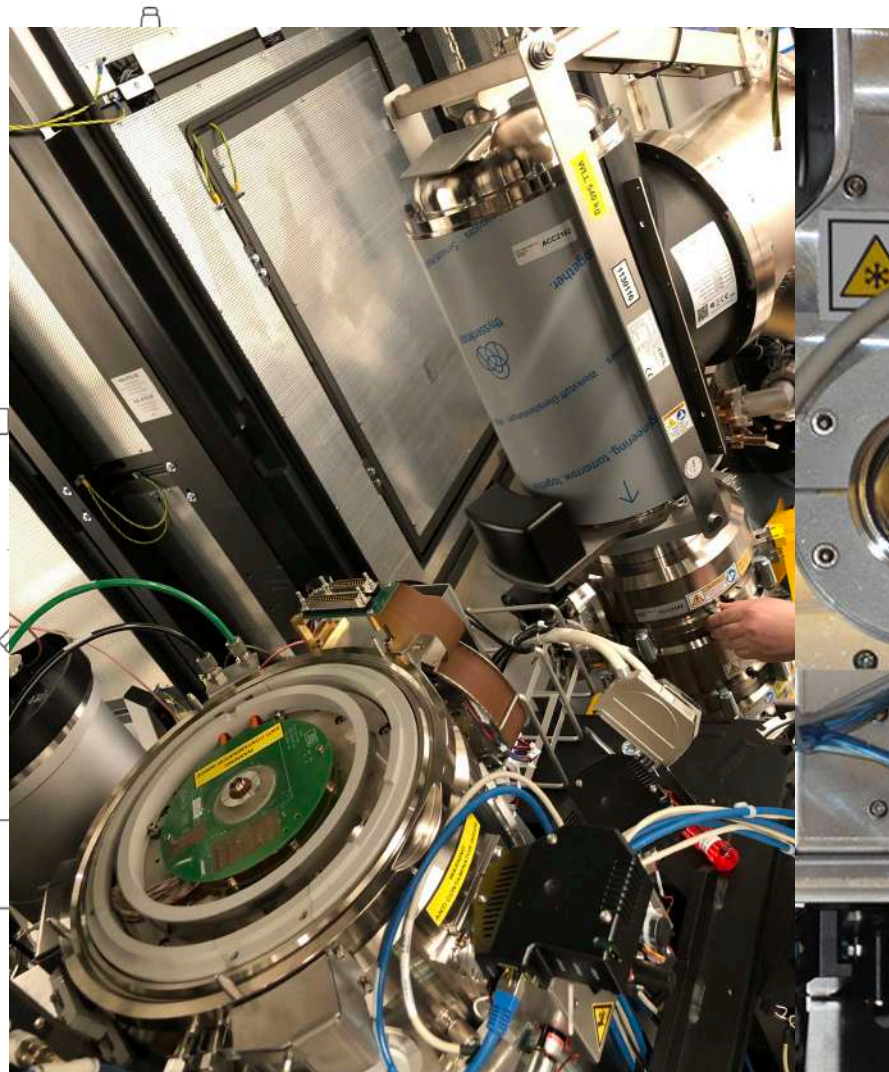
**IGP**  $10^{-9}\text{-}10^{-12} \text{ Torr}$  |  $10^{-7}\text{-}10^{-9} \text{ Pa}$







# VACUUM SYSTEMS

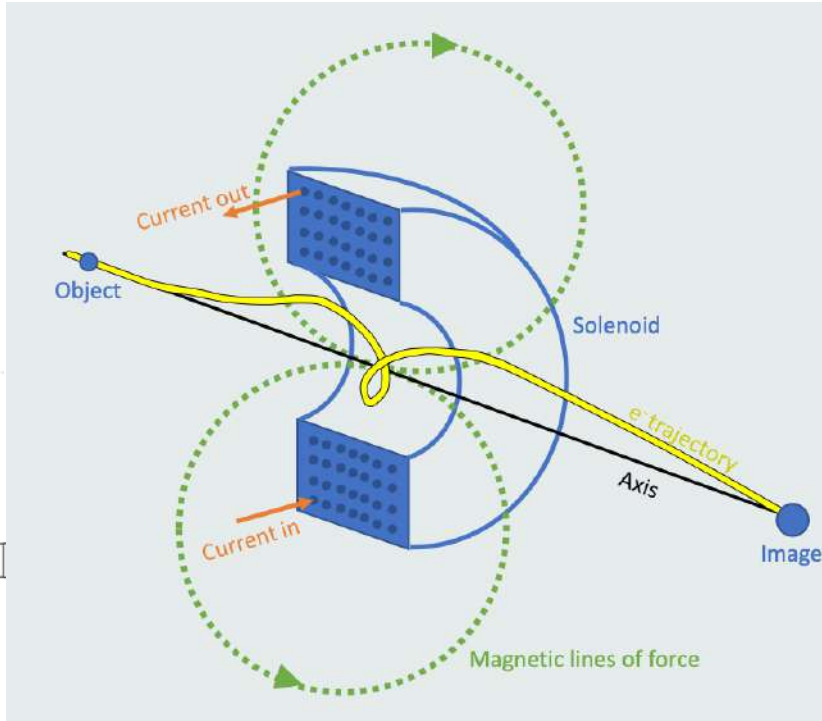
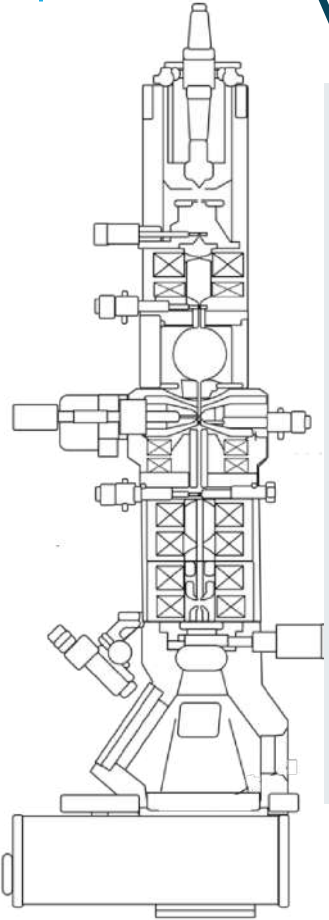






# LENSES

What types of lenses do we have?



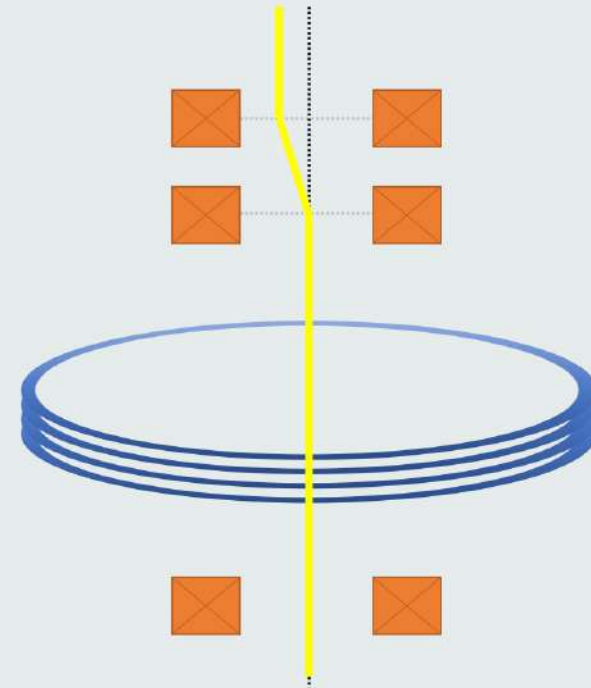
- Focus
- Magnify
- Rotate

Deflector 1 (shift)

Deflector 2 (tilt)

Lens

Stigmator



# LENSES

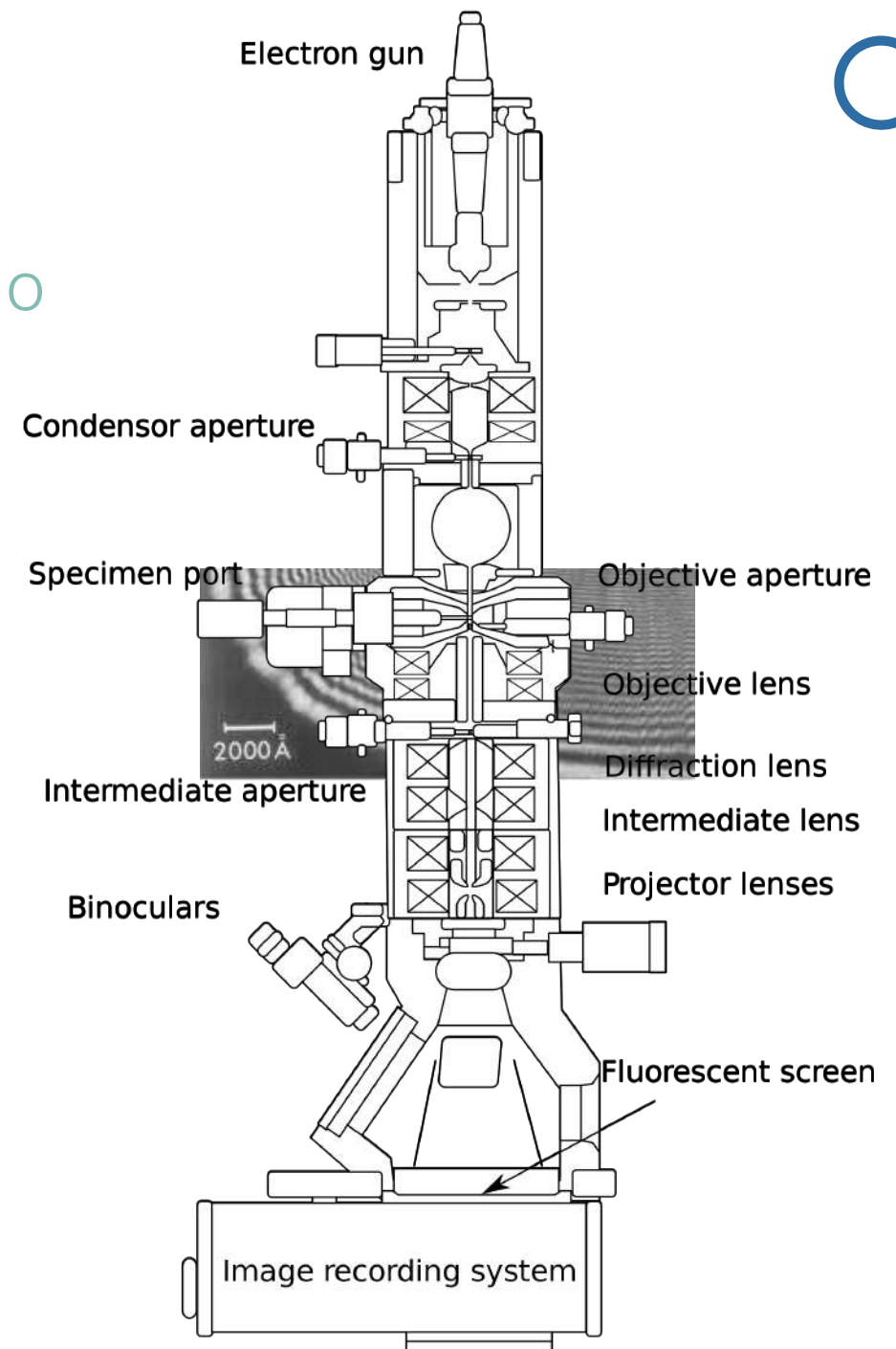
## Microscope Alignments What to do & what not to do

Do:

- Start at eucentric height and focus
- Check if it is already good before attempt
- Align from top to bottom

Not to do:

- ~~Align without a way to undo~~
- ~~Align when TEM is not stable (i.e., temperature)~~



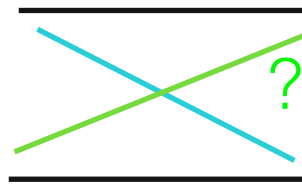


# DETECTORS

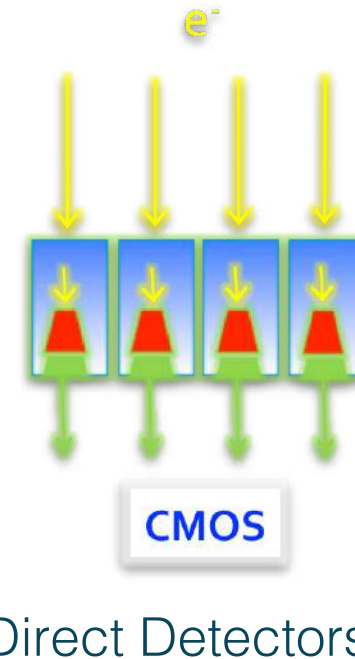
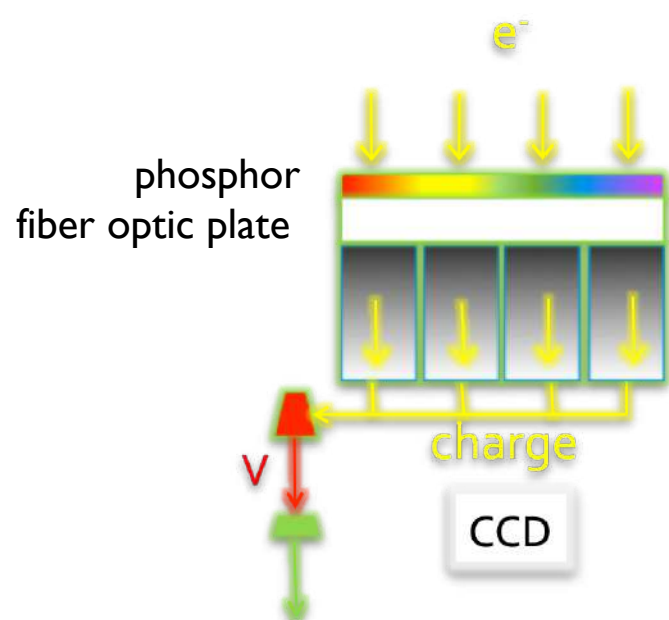
## Digital Cameras for TEM

Photon  
converted

Direct sensing



- **CCD** Charge Coupled Device
- **CMOS** Complementary Metal Oxide Semiconductor

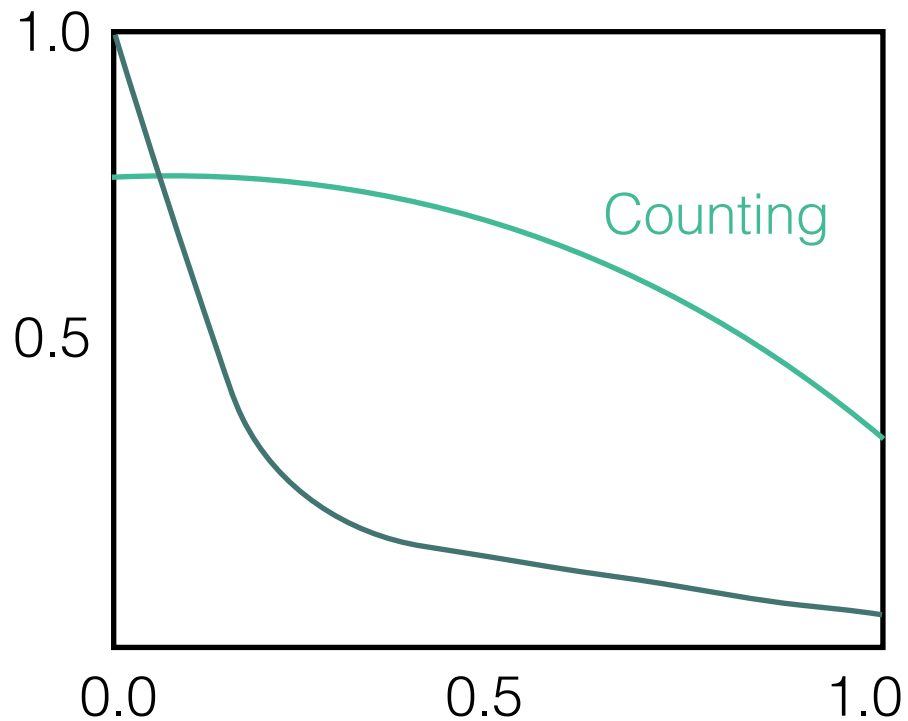




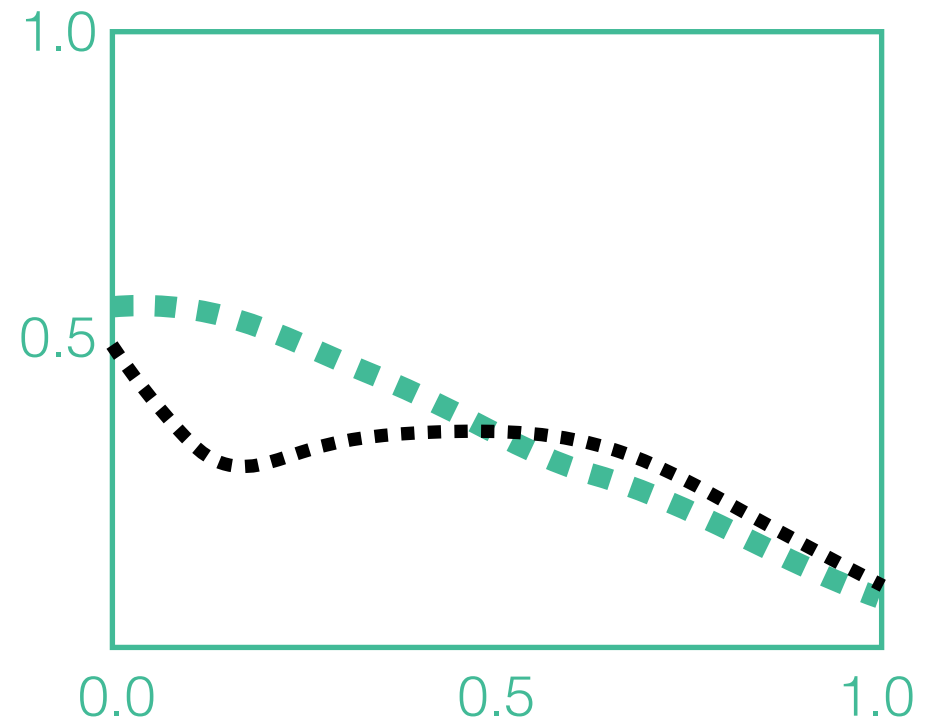
# DETECTORS

## Detector Performance Characterization

MTF (Modulation Transfer Transform)  
contribute to signal envelope



DQE (Detector Quantum Efficiency)  
S/N over spatial frequency range

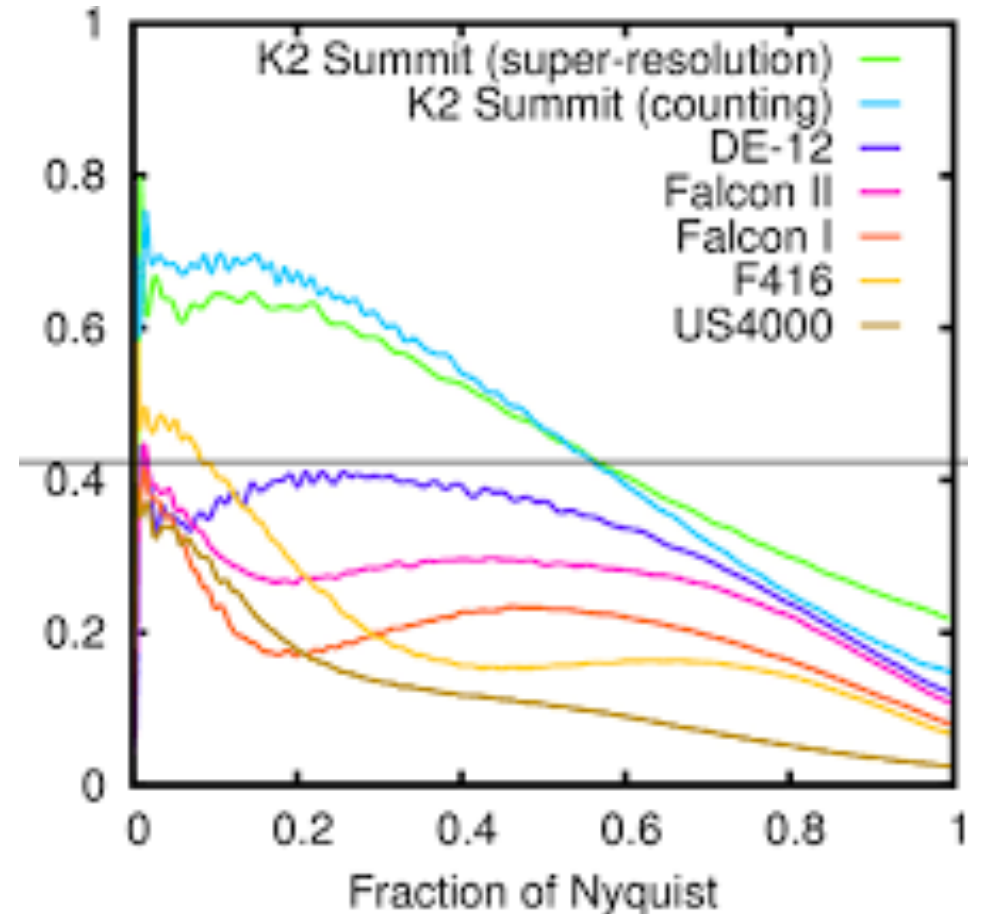
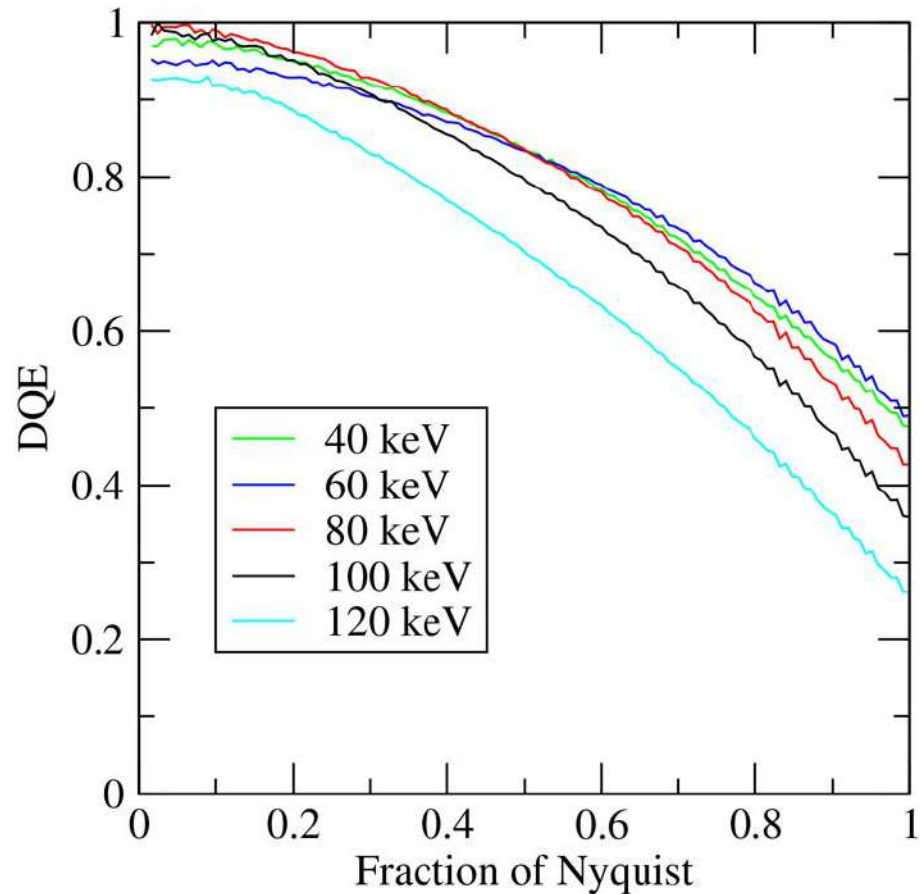






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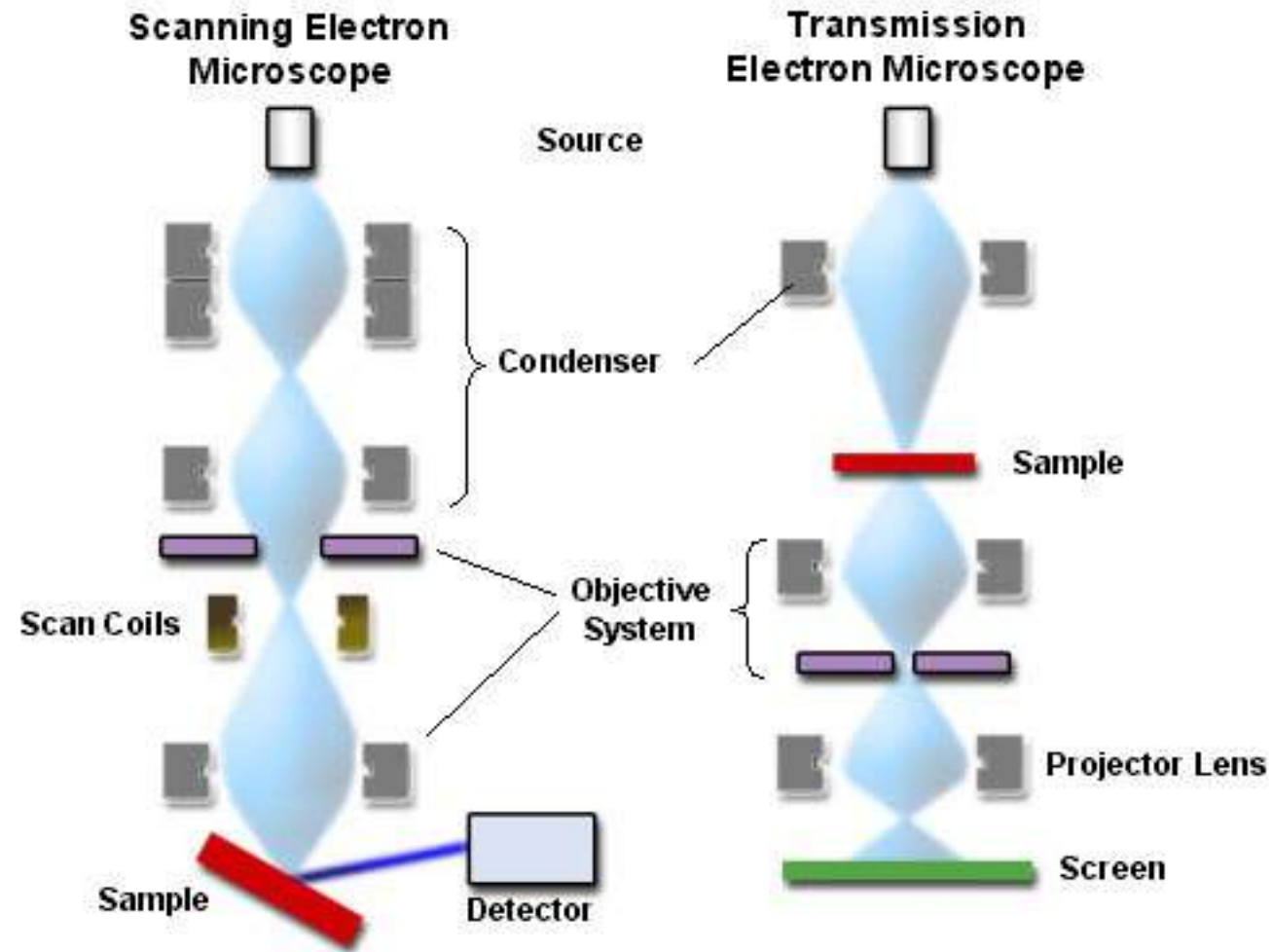
## Detector Performance Characterization



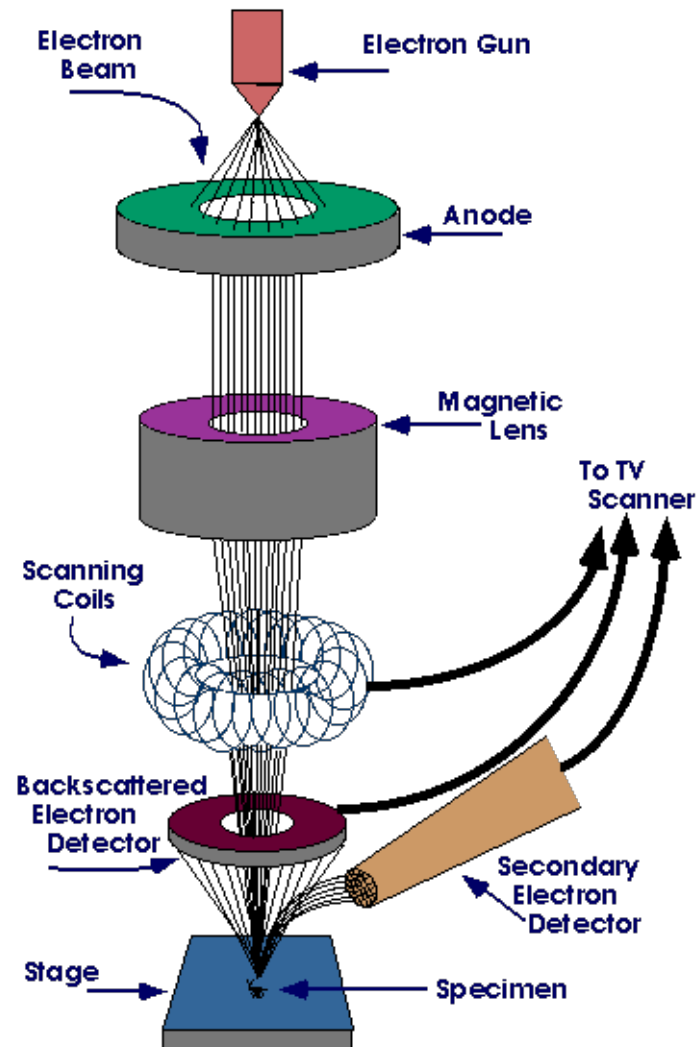
NIH P41 - National Biomedical Technology Research Resources (BTRR)



# ANATOMY OF AN SEM



# ANATOMY OF AN SEM



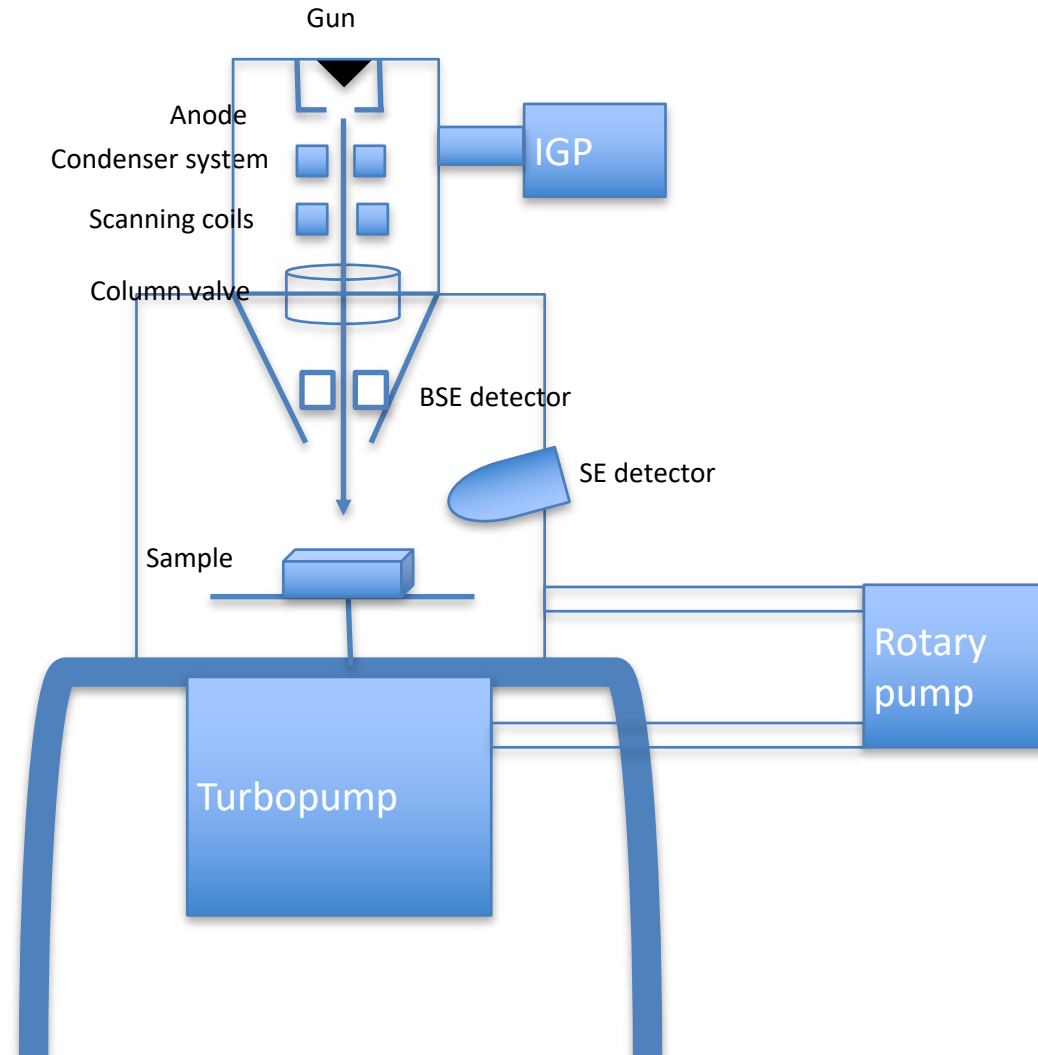
Electron gun: range from tungsten filaments in lower vacuum SEMs to FEGs which need modern high vacuum SEMs

Beam energy: 0.2 – 40 keV is focused by a condenser lens system into a spot of 0.4 – 5 nm

Beam is deflected by very fast scanning coils and rasters the sample surface

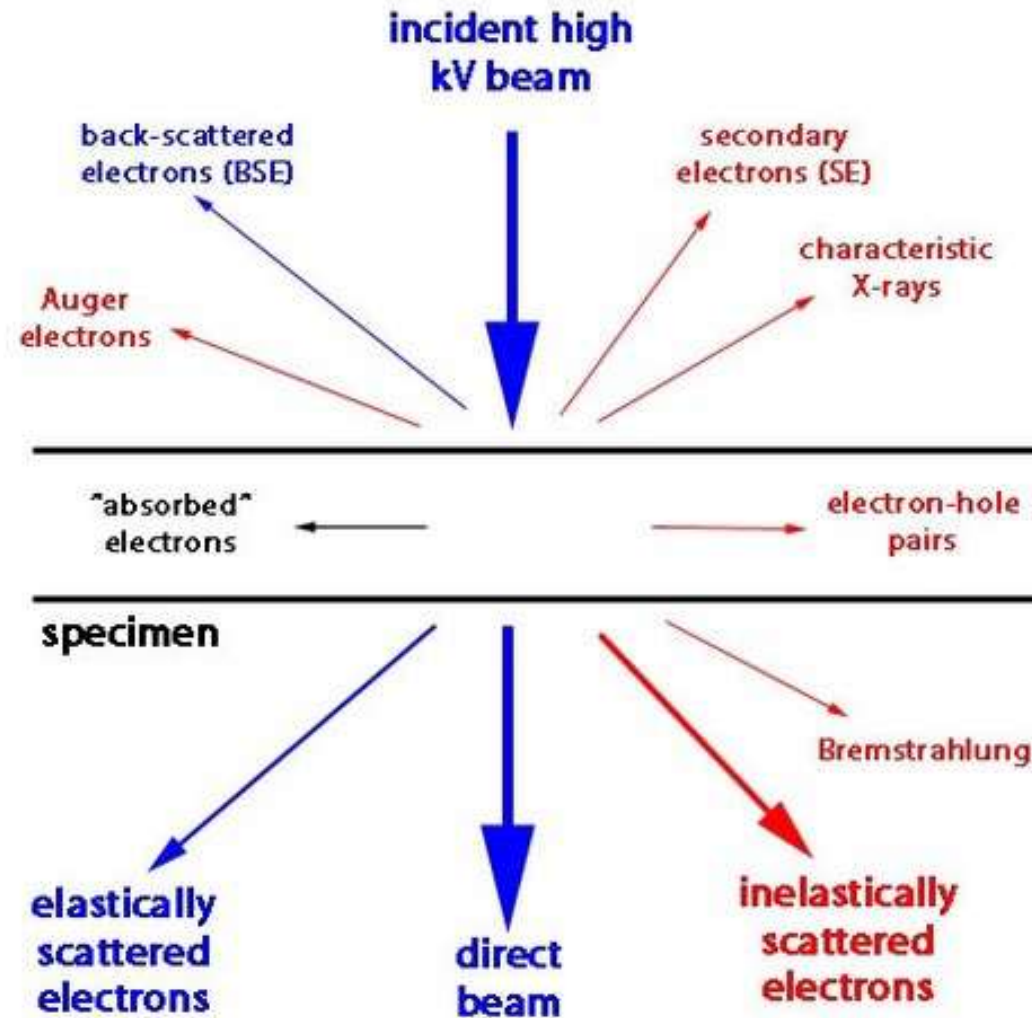
Typical resolution of SEM is between 1 and 20 nm where the record is 0.4 nm

# ANATOMY OF AN SEM — VACUUM SYSTEMS



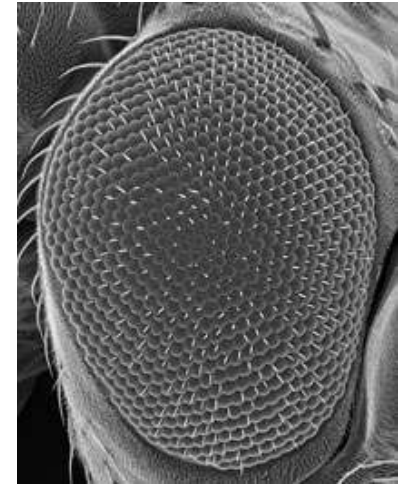
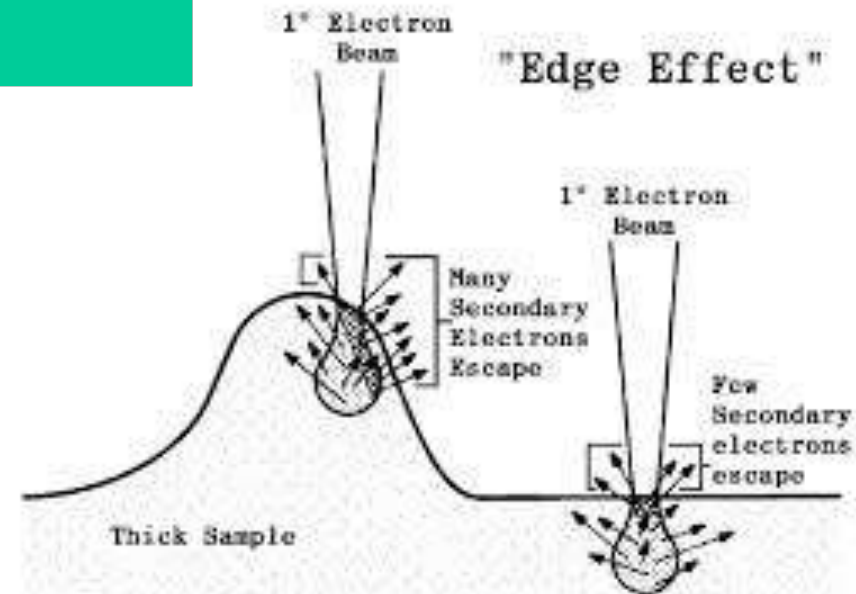
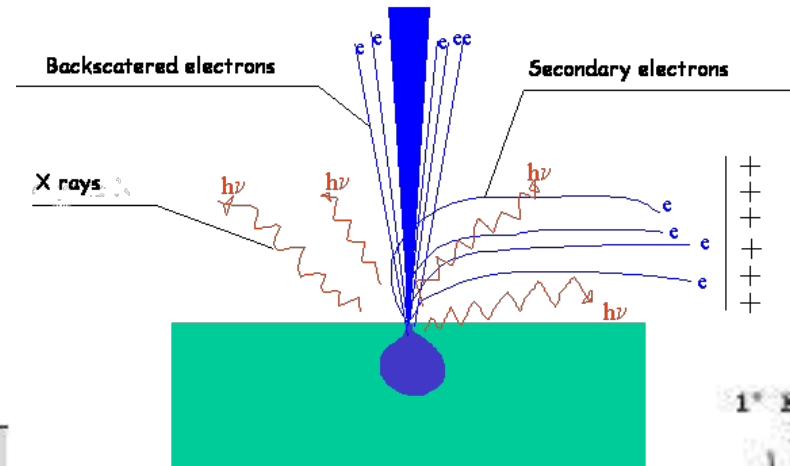
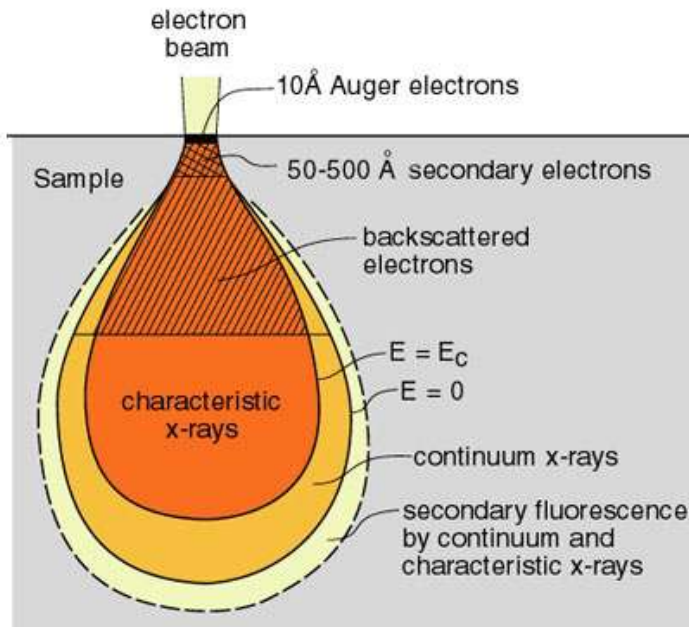


# ANATOMY OF AN SEM — BEAM SAMPLE INTERACTIONS

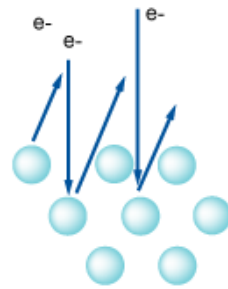


modified from Williams & Carter (1996) Fig. 1.3

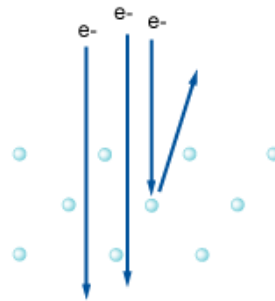
# ANATOMY OF AN SEM — BEAM SAMPLE INTERACTIONS & IMAGE FORMATION



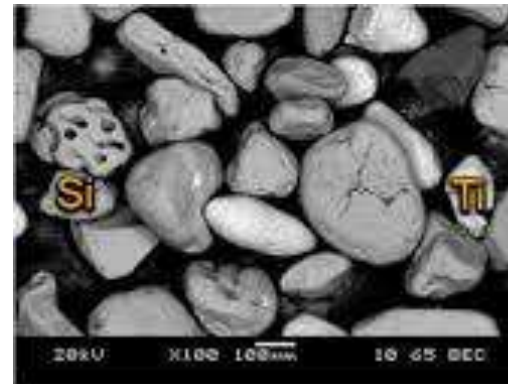
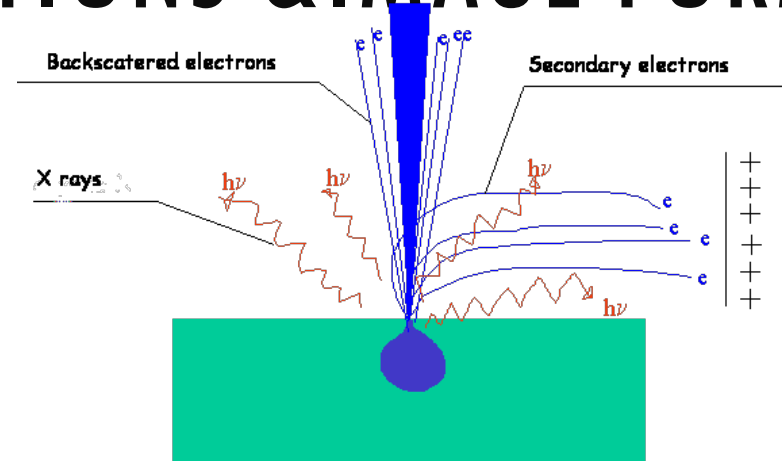
# ANATOMY OF AN SEM — BEAM SAMPLE INTERACTIONS & IMAGE FORMATION



Titanium  
atomic number 22



Silicon  
atomic number 14





# TOOLS OF THE TRADE: MICROSCOPES AND DETECTORS

Questions?





## cryoEM 001 : Single Particle Masterclass

1. Building a cryoEM toolkit
2. EM compatible samples
3. EM support films and grids
4. Sample preparation
5. Tools of the trade:  
microscopes and detectors
6. Microscope operations
7. Data collection strategies
8. Data assessment & QC
9. Data processing:
  - cryoEM IT infrastructure
  - On-the-fly feedback
  - 3D Reconstruction
10. Visualization and validation